

DUAL PERIPHERAL DRIVER

Check for Samples: [SN65472-EP](#)

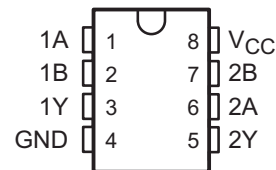
FEATURES

- Characterized for Use up to 300 mA
- High-Voltage Outputs
- No Output Latch-Up at 55 V (After Conducting 300 mA)
- Medium-Speed Switching
- Circuit Flexibility for Varied Applications and Choice of Logic Function
- TTL-Compatible Diode-Clamped Inputs
- Standard Supply Voltages

SUPPORTS INDUSTRIAL APPLICATIONS

- Controlled Baseline
- One Assembly and Test Site
- One Fabrication Site
- Available in Extended (–40°C to 125°C) Temperature Ranges ⁽¹⁾
- Extended Product Life Cycle
- Extended Product-Change Notification
- Product Traceability

**D PACKAGE
(TOP VIEW)**



(1) Custom temperature ranges available

DESCRIPTION/ORDERING INFORMATION

The SN65472 dual peripheral driver is functionally interchangeable with series SN75452B and series SN75462 peripheral drivers, but is designed for use in systems that require higher breakdown voltages than either of those series can provide at the expense of slightly slower switching speeds than series 75452B (limits are the same as series SN75462). Typical applications include high-speed logic buffers, power drivers, relay drivers, lamp drivers, MOS drivers, line drivers, and memory drivers.

The SN65472 is a dual peripheral NAND driver (assuming positive logic), with the output of the logic gates internally connected to the bases of the npn output transistors.

This device is characterized for operation from –40°C to 125°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of the Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

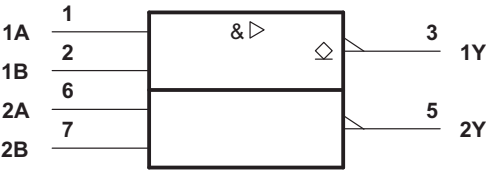
ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

ORDERING INFORMATION⁽¹⁾

T _J	PACKAGE ⁽²⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING	VID NUMBER
-40°C to 125°C	SOIC – D	Tape of 75	SN65472DEP	65472	V62/13618-01XE-T
		Reel of 2500	SN65472DREP	65472	V62/13618-01XE

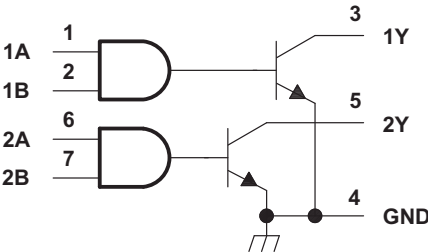
- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
(2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

LOGIC SYMBOL



This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

LOGIC DIAGRAM (POSITIVE LOGIC)

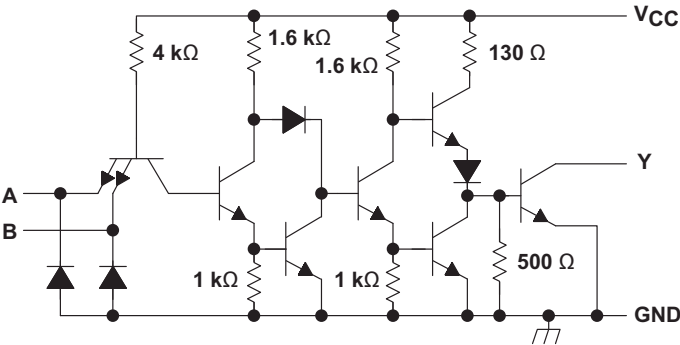


**Table 1. FUNCTION TABLE
(EACH DRIVER)**

INPUTS		Y ⁽¹⁾
A	B	
L	L	H (Off state)
L	H	H (Off state)
H	L	H (Off state)
H	H	L (On state)

(1) positive logic: $Y = \overline{A}\overline{B}$ or $\overline{A} + \overline{B}$

SCHEMATIC (EACH DRIVER)



Resistor values shown are nominal.

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V _{CC}	Supply voltage range ⁽²⁾		7	V
V _I	Input voltage		5.5	V
	Inter-emitter voltage ⁽³⁾		5.5	V
V _O	Off-state output voltage		70	V
I _O	Continuous collector or output current ⁽⁴⁾		400	mA
	Peak collector or output current (t _w ≤ 10 ms, duty cycle ≤ 50%) ⁽⁴⁾		500	mA
T _J	Absolute maximum junction temperature range	–40	150	°C
T _{stg}	Storage temperature range	–65	150	°C

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) Voltage values are with respect to the network GND, unless otherwise specified.
- (3) This is the voltage between two emitters, A and B.
- (4) Both halves of these dual circuits may conduct rated current simultaneously; however, power dissipation averaged over a short time interval must fall within the continuous dissipation rating.

THERMAL INFORMATION

THERMAL METRIC ⁽¹⁾		SN65472-EP	UNITS
		D	
		8 PINS	
θ _{JA}	Junction-to-ambient thermal resistance ⁽²⁾	115.3	°C/W
θ _{JCTop}	Junction-to-case (top) thermal resistance ⁽³⁾	59.7	
θ _{JB}	Junction-to-board thermal resistance ⁽⁴⁾	56.2	
ψ _{JT}	Junction-to-top characterization parameter ⁽⁵⁾	13.5	
ψ _{JB}	Junction-to-board characterization parameter ⁽⁶⁾	55.6	
θ _{JCbot}	Junction-to-case (bottom) thermal resistance ⁽⁷⁾	N/A	

- (1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ_{JT}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA}, using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ_{JB}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA}, using a procedure described in JESD51-2a (sections 6 and 7).
- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.75	5	5.25	V
V _{IH}	High-level input voltage	2.1			V
V _{IL}	Low-level input voltage			0.8	V
T _A	Operating free-air temperature range	–40		85	°C
T _J	Operating virtual junction temperature	–40		125	°C

ELECTRICAL CHARACTERISTICS

These specifications apply for $-40^{\circ}\text{C} \leq T_J \leq 125^{\circ}\text{C}$ (unless otherwise noted)

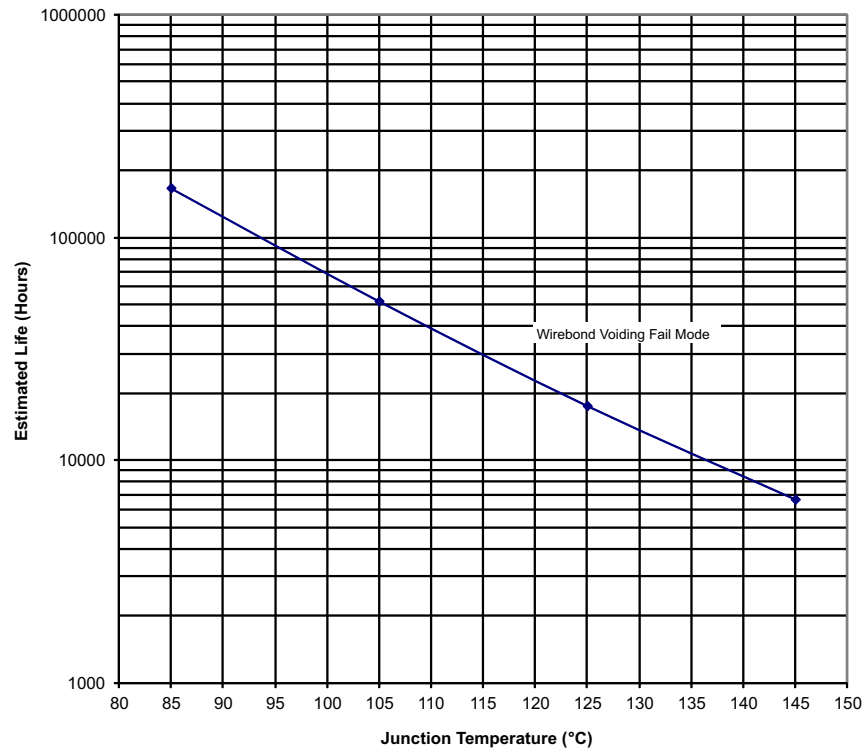
PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V_{IK} Input clamp voltage	$V_{CC} = 4.75\text{ V}$, $I_I = -12\text{ mA}$		-1.2	-1.5	V
I_{OH} High-level output current	$V_{CC} = 4.75\text{ V}$, $V_{IH} = 2\text{ V}$, $V_{OH} = 70\text{ V}$			270	μA
V_{OL} Low level output voltage	$V_{CC} = 4.75\text{ V}$, $V_{IL} = 0.8\text{ V}$, $I_{OL} = 100\text{ mA}$		0.25	0.4	V
	$V_{CC} = 4.75\text{ V}$, $V_{IL} = 0.8\text{ V}$, $I_{OL} = 300\text{ mA}$		0.5	0.75	
I_I Input current at maximum input voltage	$V_{CC} = 5.25\text{ V}$, $V_I = 5.5\text{ V}$			1	mA
I_{IH} High-level input current	$V_{CC} = 5.25\text{ V}$, $V_I = 2.4\text{ V}$			44	μA
I_{IL} Low-level input current	$V_{CC} = 5.25\text{ V}$, $V_I = 0.4\text{ V}$		-1	-1.6	mA
I_{CCH} Supply current, outputs high	$V_{CC} = 5.25\text{ V}$, $V_I = 5\text{ V}$		13	17	mA
I_{CCL} Supply current, outputs low	$V_{CC} = 5.25\text{ V}$, $V_I = 0$		61	76	mA

(1) All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^{\circ}\text{C}$.

SWITCHING CHARACTERISTICS

$V_{CC} = 5\text{ V}$, $T_A = 25^{\circ}\text{C}$, over operating free-air temperature range (unless otherwise noted)

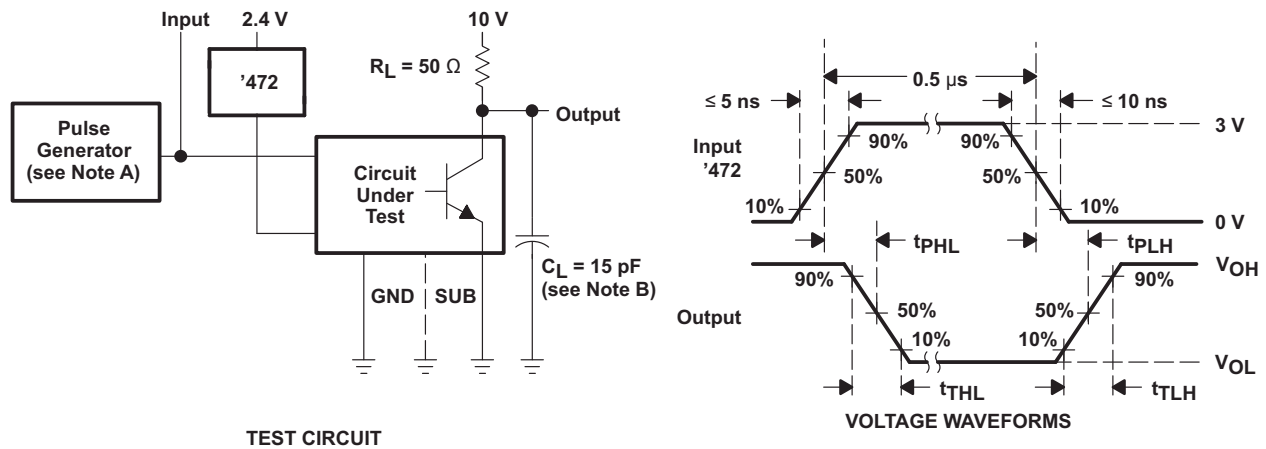
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH} Propagation delay time, low-to-high-level output	$I_O \approx 200\text{ mA}$, $C_L = 15\text{ pF}$, $R_L = 50\ \Omega$, see Figure 2		45	65	ns
t_{PHL} Propagation delay time, high-to-low-level output	$I_O \approx 200\text{ mA}$, $C_L = 15\text{ pF}$, $R_L = 50\ \Omega$, see Figure 2		30	50	ns
t_{TLH} Transition time, low-to-high-level output	$I_O \approx 200\text{ mA}$, $C_L = 15\text{ pF}$, $R_L = 50\ \Omega$, see Figure 2		13	25	ns
t_{THL} Transition time, high-to-low-level output	$I_O \approx 200\text{ mA}$, $C_L = 15\text{ pF}$, $R_L = 50\ \Omega$, see Figure 2		10	20	ns
V_{OH} High level output voltage after switching	$V_S = 55\text{ V}$, $I_O \approx 300\text{ mA}$, see Figure 3	$V_S - 18$			mV



- (1) See Datasheet for Absolute Maximum and minimum Recommended Operating Conditions.
- (2) Silicon operating life design goal is 10 years at 105°C junction temperature (does not include package interconnect life).

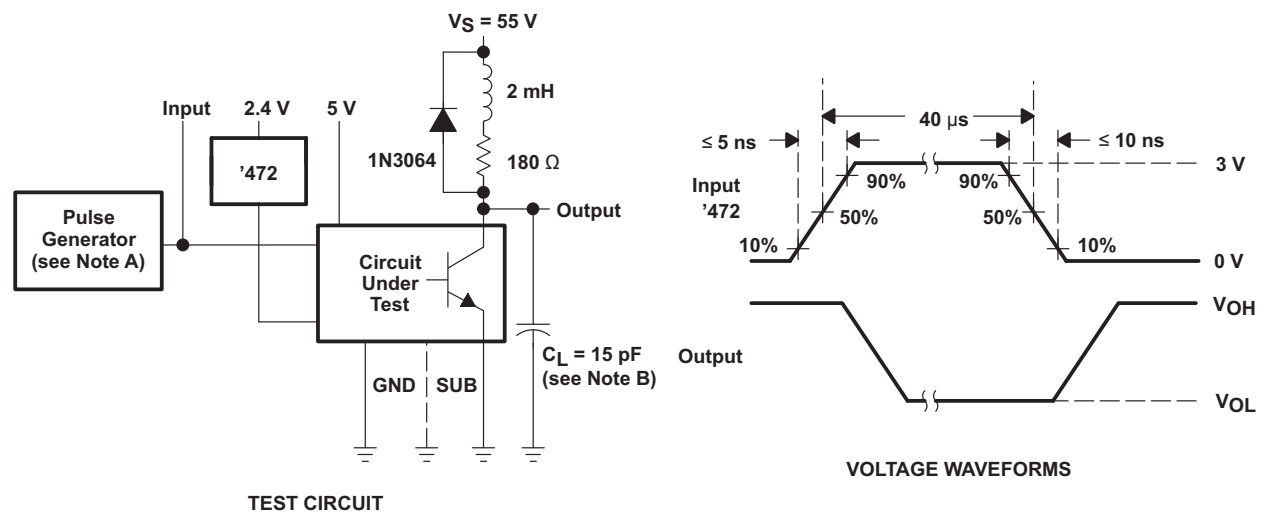
Figure 1. SN65472-EP Wirebond Life Derating Chart

PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: $PRR \leq 1 \text{ MHz}$, $Z_O \approx 50 \Omega$.
 B. C_L includes probe and jig capacitance.

Figure 2. Switching Times



NOTES: A. The pulse generator has the following characteristics: $PRR \leq 12.5 \text{ kHz}$, $Z_O \approx 50 \Omega$.
 B. C_L includes probe and jig capacitance.

Figure 3. Latch-Up Test

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN65472DEP	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65472	Samples
SN65472DREP	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65472	Samples
V62/13618-01XE	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65472	Samples
V62/13618-01XE-T	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	65472	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

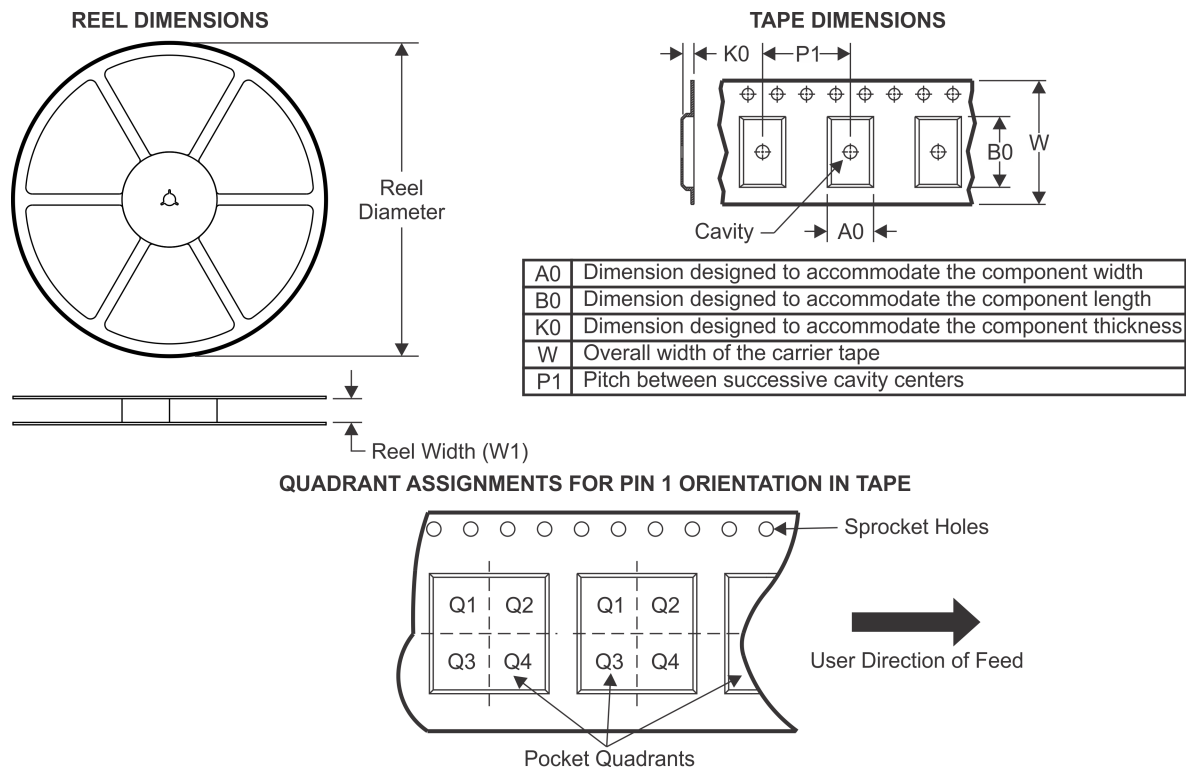
(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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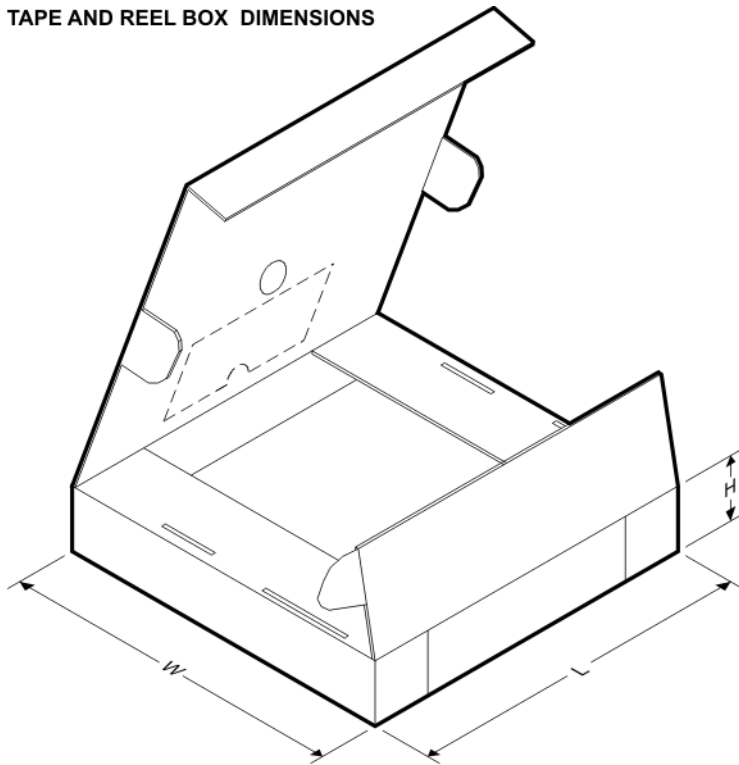
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TAPE AND REEL INFORMATION


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65472DREP	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS

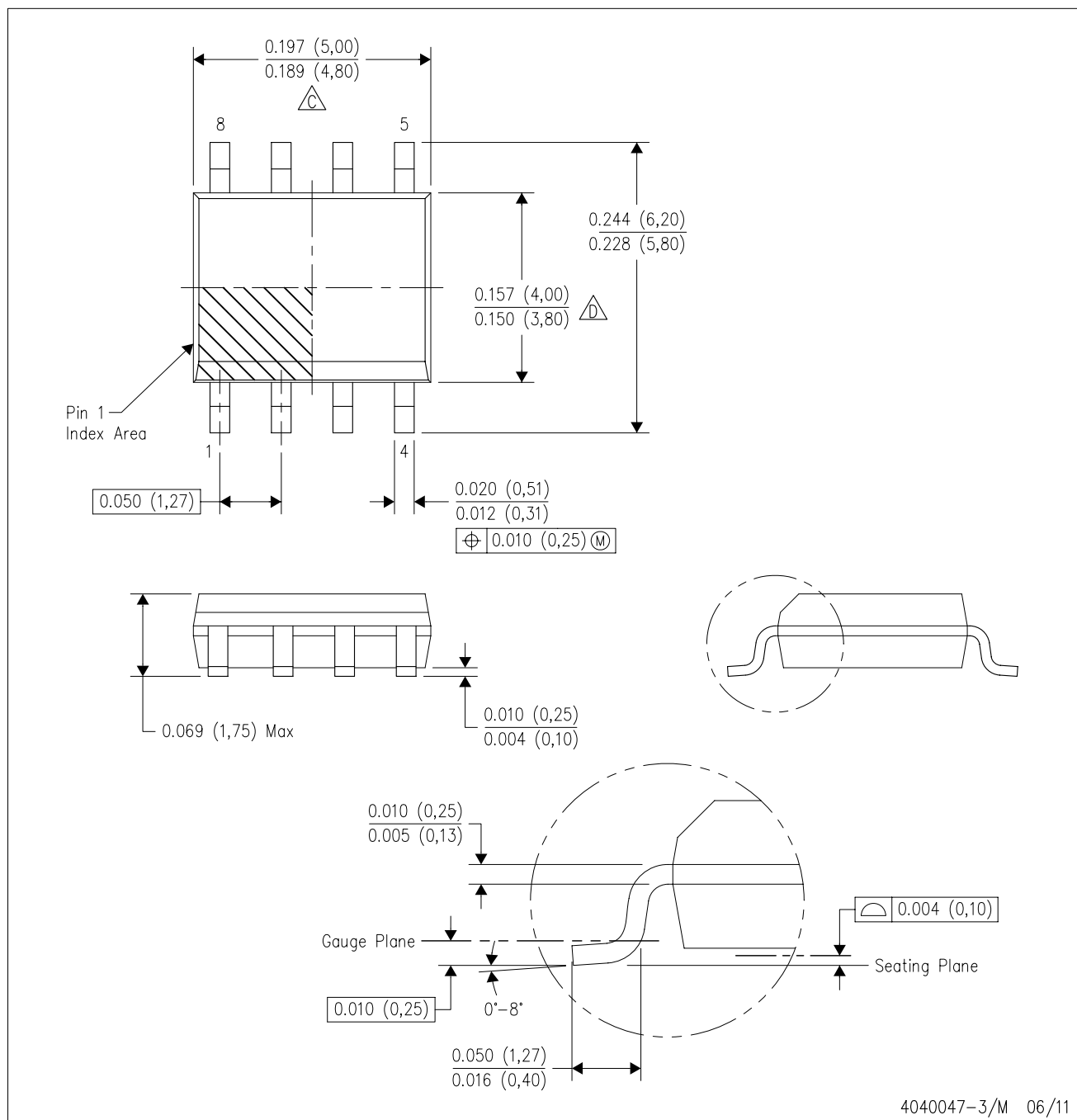


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65472DREP	SOIC	D	8	2500	340.5	338.1	20.6

D (R-PDSO-G8)

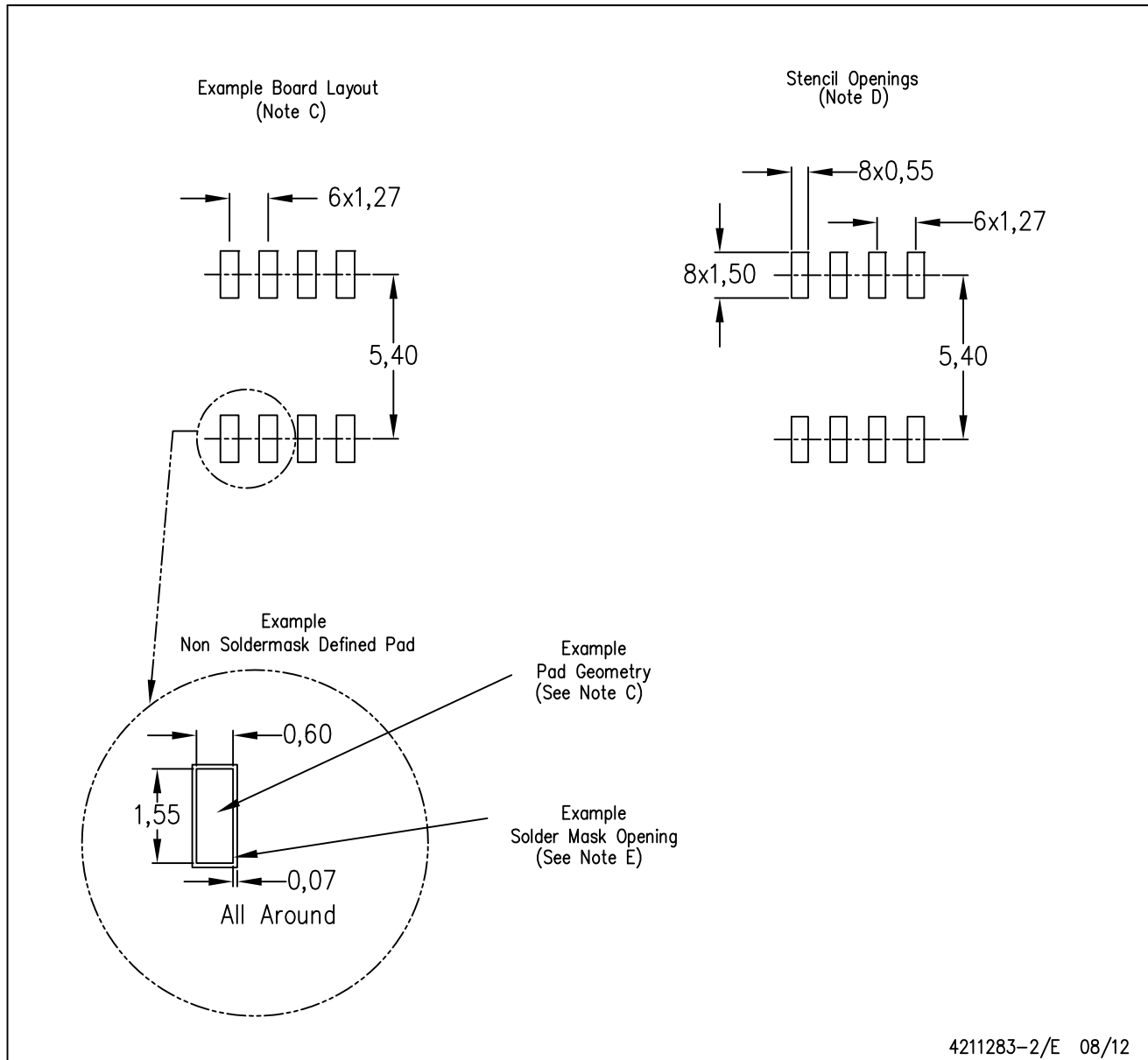
PLASTIC SMALL OUTLINE



- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - $\triangle C$ Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
 - $\triangle D$ Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
 - E. Reference JEDEC MS-012 variation AA.

D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



4211283-2/E 08/12

- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Publication IPC-7351 is recommended for alternate designs.
 - D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 - E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

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